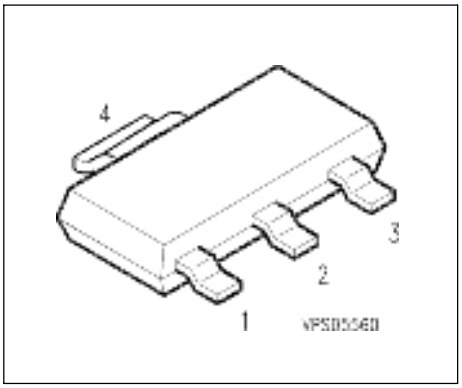
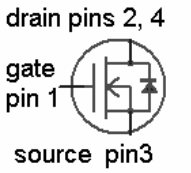
SIPMOS ® Small-Signal Transistor

- N channel
- Enhancement mode
- Avalanche rated
- $V_{GS(th)}$= 2.0... 4.0 V
- Pb-free lead plating; RoHS compliant
- Qualified according to AEC Q101





Pin 1	Pin 2	Pin 3	Pin 4
G	D	S	D

Type	V_{DS}	I_D	$R_{DS(on)}$	Package	Marking
BSP300	800 V	0.19 A	20 Ω	PG-SOT223	BSP300

Type	RoHS compliant	Tape and Reel Information	Packaging
BSP300	Yes	L6327	Dry

Maximum Ratings

Parameter	Symbol	Values	Unit
Continuous drain current T_A = 25 °C	I_D	0.19	A
DC drain current, pulsed T_A = 25 °C	I_{Dpuls}	0.76	
Avalanche energy, single pulse I_D = 0.8 A, V_{DD} = 50 V, R_{GS} = 25 Ω L = 105 mH, T_j = 25 °C	E_{AS}	36	mJ
Gate source voltage	V_{GS}	± 20	V
Power dissipation T_A = 25 °C	P_{tot}	1.8	W
ESD Class JESD22-A114-HBM		Class 1a	

Maximum Ratings

Parameter	Symbol	Values	Unit
Chip or operating temperature	T_j	-55 ... + 150	°C
Storage temperature	T_{stg}	-55 ... + 150	
Thermal resistance, chip to ambient air 1)	R_{thJA}	≤ 70	K/W
Thermal resistance, junction-soldering point 1)	R_{thJS}	≤ 14	
DIN humidity category, DIN 40 040		E	
IEC climatic category, DIN IEC 68-1		55 / 150 / 56	

1) Transistor on epoxy pcb 40 mm x 40 mm x 1,5 mm with 6 cm^2 copper area for drain connection

Electrical Characteristics, at T_j = 25°C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Static Characteristics					
Drain- source breakdown voltage V_{GS} = 0 V, I_D = 0.25 mA, T_j = 25 °C	$V_{(BR)DSS}$	800	-	-	V
Gate threshold voltage V_{GS}=V_{DS}, I_D = 1 mA	$V_{GS(th)}$	2	3	4	
Zero gate voltage drain current V_{DS} = 800 V, V_{GS} = 0 V, T_j = 25 °C V_{DS} = 800 V, V_{GS} = 0 V, T_j = 125 °C	I_{DSS}	- -	0.1 10	1 100	µA
Gate-source leakage current V_{GS} = 20 V, V_{DS} = 0 V	I_{GSS}	-	10	100	nA
Drain-Source on-state resistance V_{GS} = 10 V, I_D = 0.19 A	$R_{DS(on)}$	-	15	20	Ω

Electrical Characteristics, at T_j = 25°C, unless otherwise specified

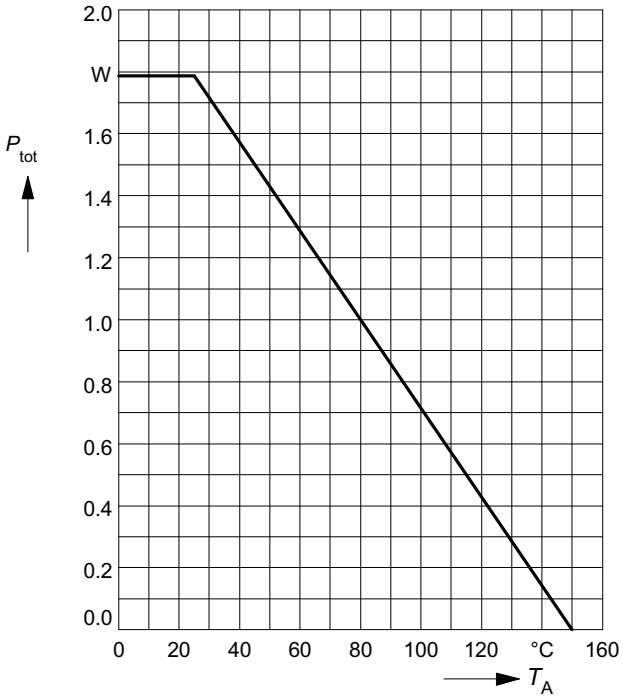
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Dynamic Characteristics					
Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}$, I_D = 0.19 A	g_{fs}	0.06	0.27	-	S
Input capacitance V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz	C_{iss}	-	170	230	pF
Output capacitance V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz	C_{oss}	-	20	30	
Reverse transfer capacitance V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz	C_{rss}	-	10	15	
Turn-on delay time V_{DD} = 30 V, V_{GS} = 10 V, I_D = 0.25 A R_{GS} = 50 Ω	$t_{d(on)}$	-	7	11	ns
Rise time V_{DD} = 30 V, V_{GS} = 10 V, I_D = 0.25 A R_{GS} = 50 Ω	t_r	-	16	24	
Turn-off delay time V_{DD} = 30 V, V_{GS} = 10 V, I_D = 0.25 A R_{GS} = 50 Ω	$t_{d(off)}$	-	27	36	
Fall time V_{DD} = 30 V, V_{GS} = 10 V, I_D = 0.25 A R_{GS} = 50 Ω	t_f	-	21	28	

Electrical Characteristics, at T_j = 25°C, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Reverse Diode					
Inverse diode continuous forward current T_A = 25 °C	I_S	-	-	0.19	A
Inverse diode direct current,pulsed T_A = 25 °C	I_{SM}	-	-	0.76	
Inverse diode forward voltage V_{GS} = 0 V, I_F = 0.38 A, T_j = 25 °C	V_{SD}	-	1	1.4	V
Reverse recovery time V_R = 30 V, I_F=I_S = 0 , di_F/dt = 100 A/µs	t_{rr}	-	95	-	ns
Reverse recovery charge V_R = 30 V, I_F=I_S = 0 , di_F/dt = 100 A/µs	Q_{rr}	-	0.25	-	µC

Power dissipation

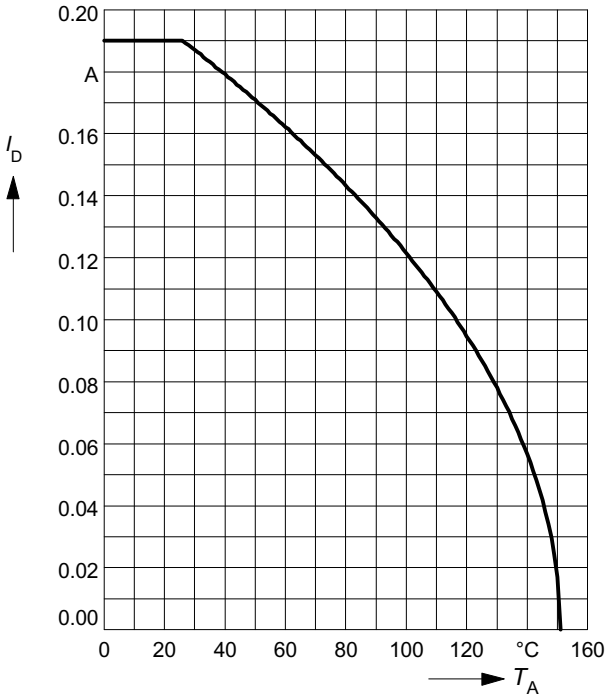
$P_{tot} = f(T_A)$



Drain current

$I_D = f(T_A)$

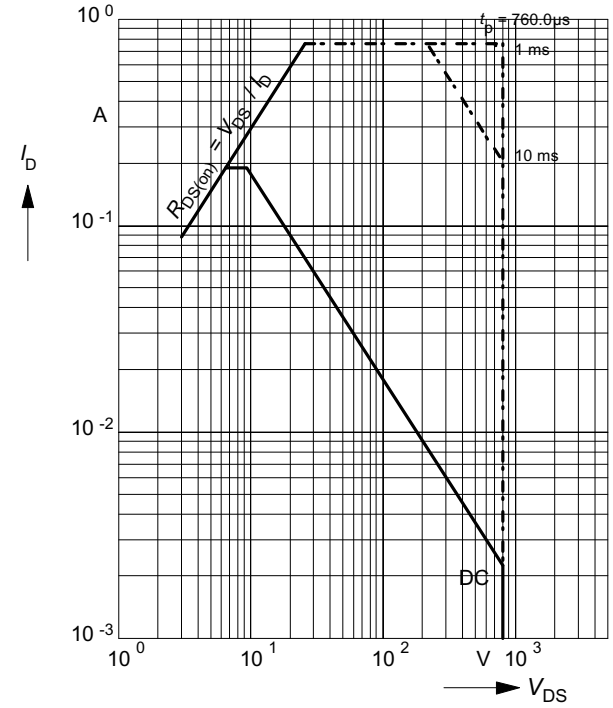
parameter: $V_{GS} \geq 10$ V



Safe operating area

$I_D = f(V_{DS})$

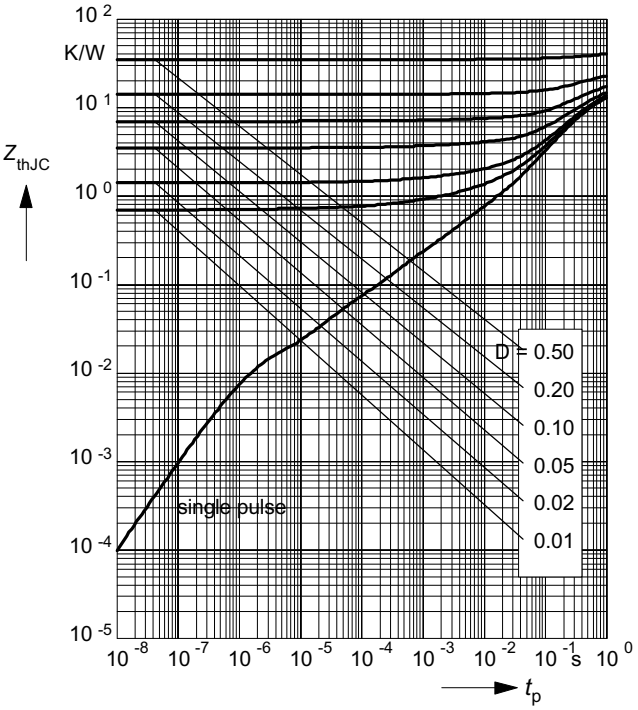
parameter: $D = 0.01$, $T_C = 25$°C



Transient thermal impedance

$Z_{th\,JA} = f(t_p)$

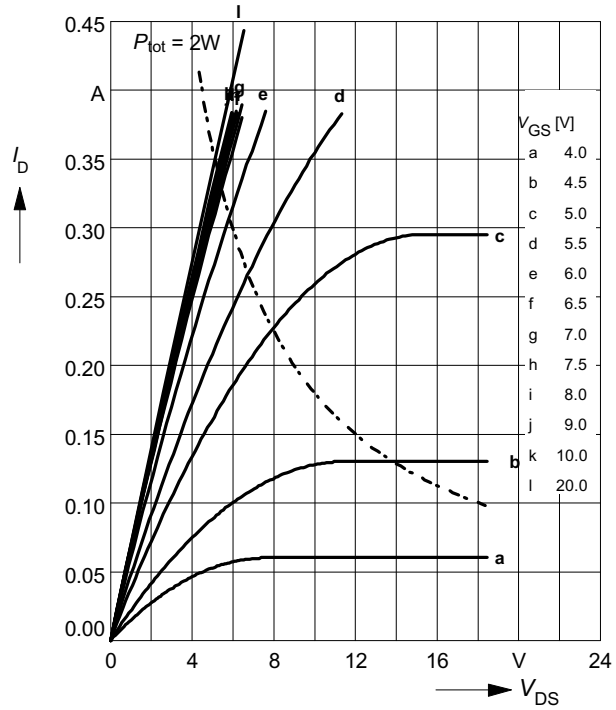
parameter: $D = t_p / T$



Typ. output characteristics

$I_D = f(V_{DS})$

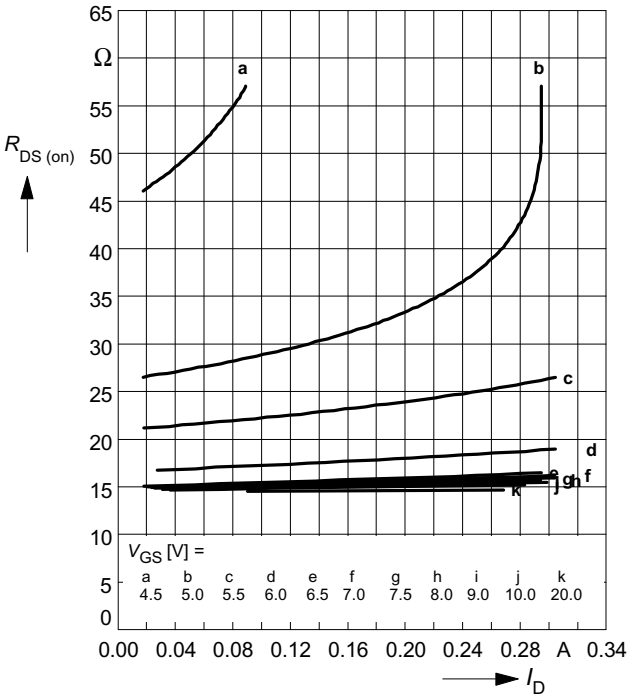
parameter: t_p = 80 µs , T_j = 25 °C



Typ. drain-source on-resistance

$R_{DS\ (on)} = f(I_D)$

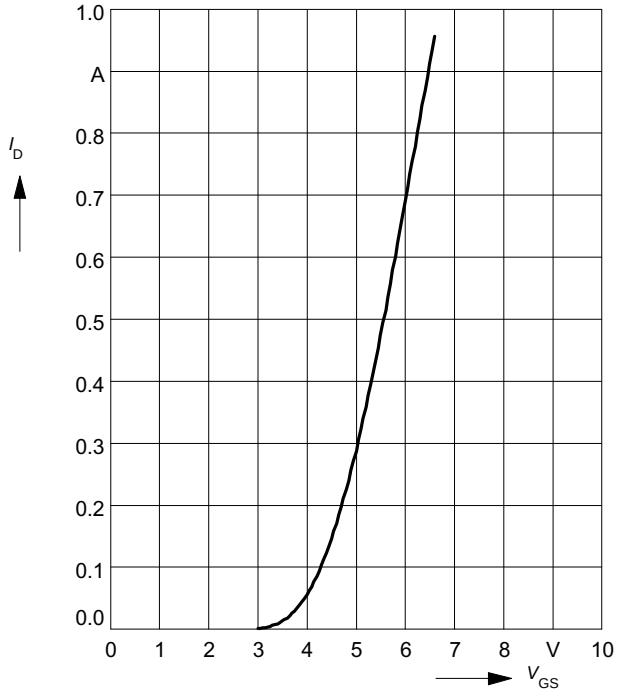
parameter: t_p = 80 µs, T_j = 25 °C



Typ. transfer characteristics $I_D = f(V_{GS})$

parameter: t_p = 80 µs

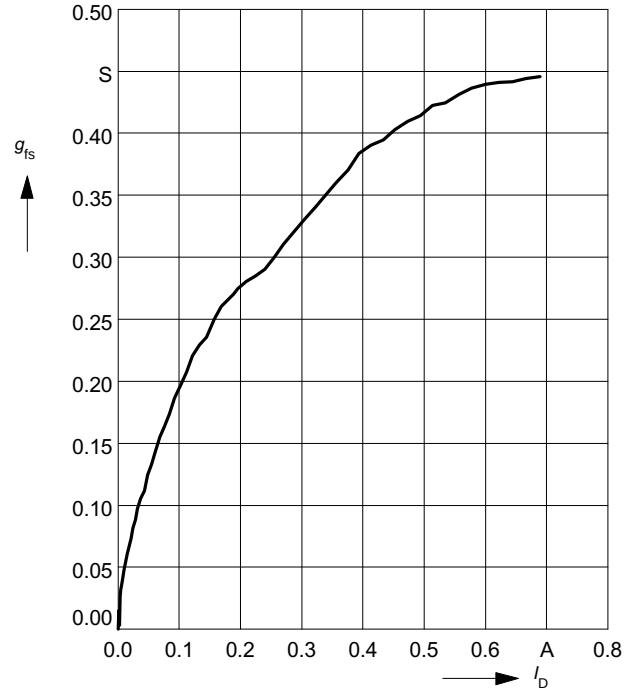
$V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$



Typ. forward transconductance $g_{fs} = f(I_D)$

parameter: t_p = 80 µs,

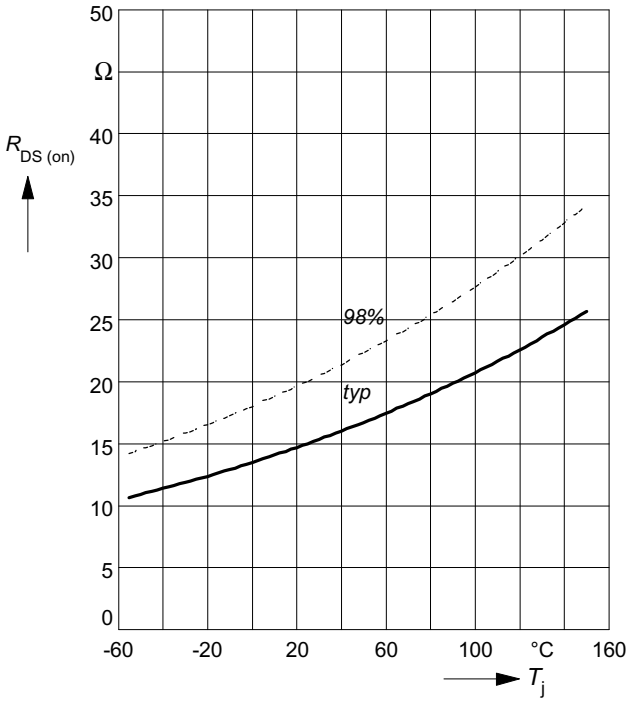
$V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$



Drain-source on-resistance

$R_{DS\ (on)} = f(T_j)$

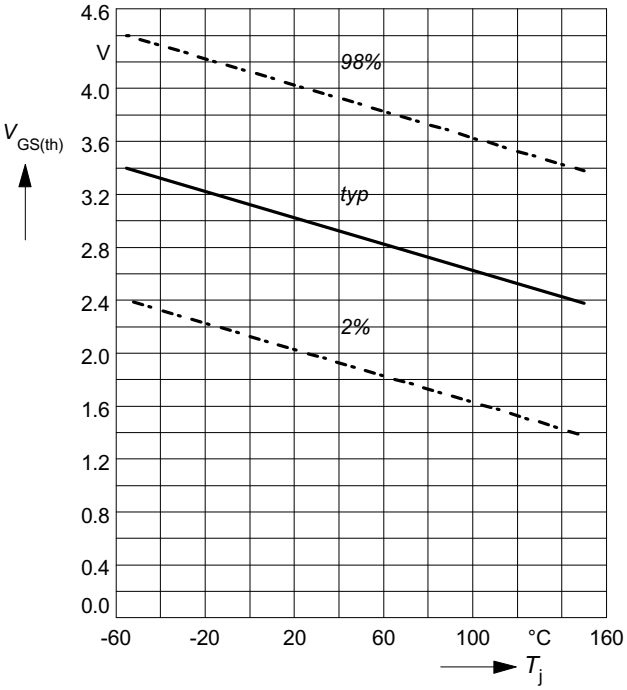
parameter: I_D = 0.19 A, V_{GS} = 10 V



Gate threshold voltage

$V_{GS\ (th)} = f(T_j)$

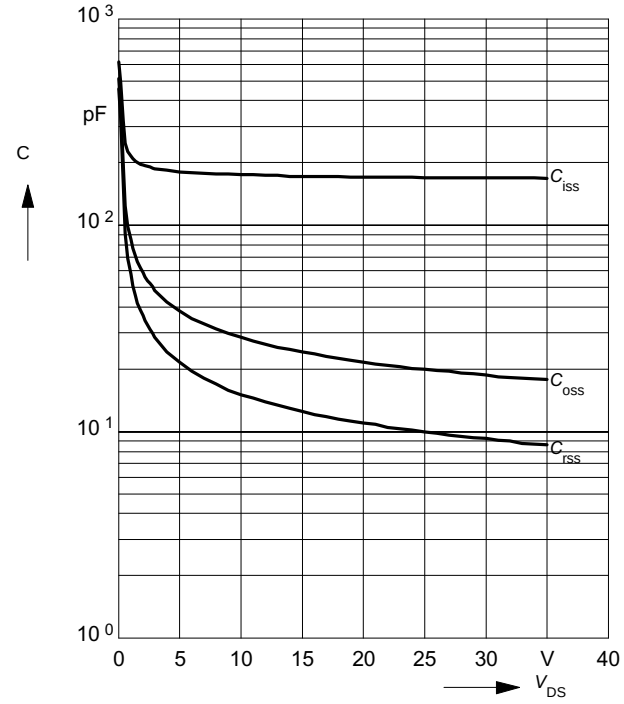
parameter: $V_{GS} = V_{DS}$, I_D = 1 mA



Typ. capacitances

$C = f(V_{DS})$

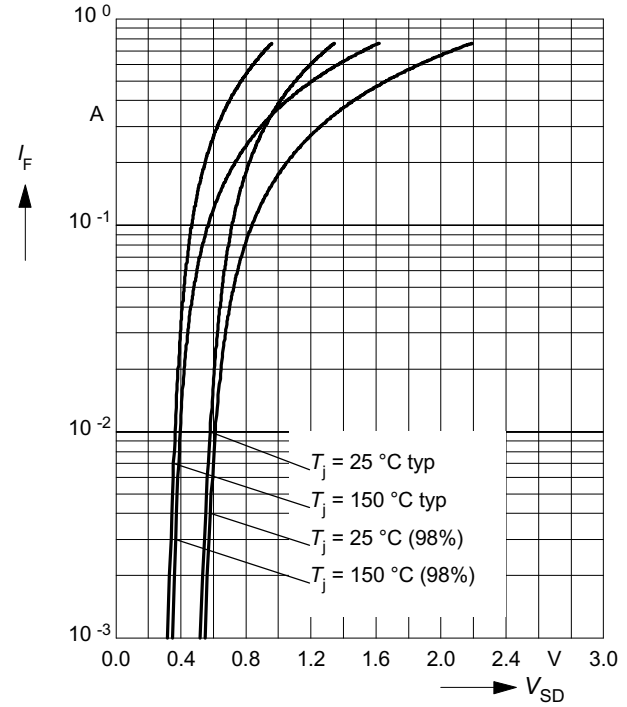
parameter: V_{GS}=0V, f = 1 MHz



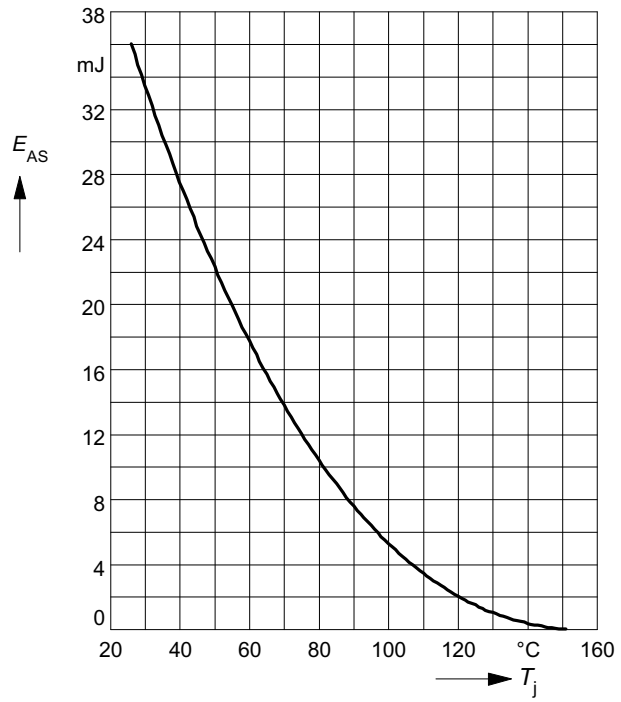
Forward characteristics of reverse diode

$I_F = f(V_{SD})$

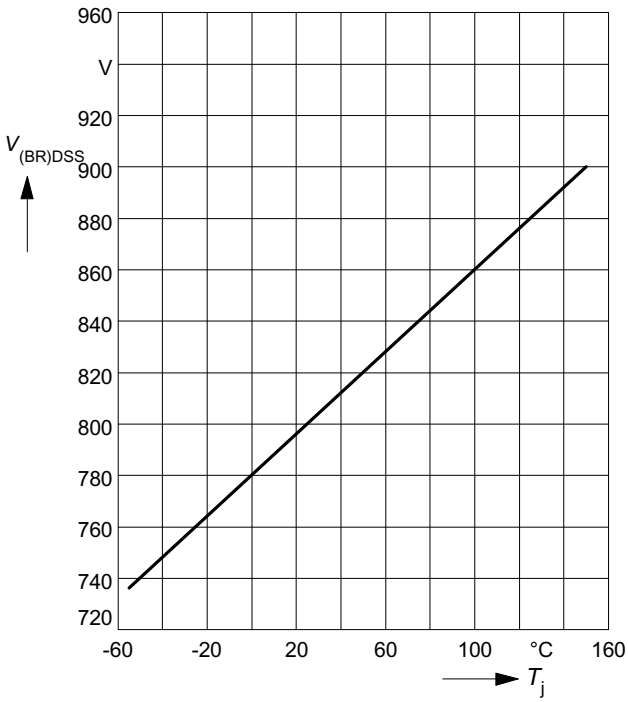
parameter: T_j, t_p = 80 µs



Avalanche energy $E_{AS} = f(T_j)$
parameter: I_D = 0.8 A, V_{DD} = 50 V
R_{GS} = 25 Ω, L = 105 mH



Drain-source breakdown voltage
$V_{(BR)DSS} = f(T_j)$



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